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# STM32F303xB STM32F303xC

ARM®-based Cortex®-M4 32b MCU+FPU, up to 256KB Flash+ 48KB SRAM, 4 ADCs, 2 DAC ch., 7 comp, 4 PGA, timers, 2.0-3.6 V

Datasheet - production data

#### **Features**

- Core: ARM® Cortex®-M4 32-bit CPU with FPU (72 MHz max), single-cycle multiplication and HW division, 90 DMIPS (from CCM), DSP instruction and MPU (memory protection unit)
- Operating conditions:
  - V<sub>DD</sub>, V<sub>DDA</sub> voltage range: 2.0 V to 3.6 V
- Memories
  - 128 to 256 Kbytes of Flash memory
  - Up to 40 Kbytes of SRAM, with HW parity check implemented on the first 16 Kbytes.
  - Routine booster: 8 Kbytes of SRAM on instruction and data bus, with HW parity check (CCM)
- CRC calculation unit
- Reset and supply management
  - Power-on/Power-down reset (POR/PDR)
  - Programmable voltage detector (PVD)
  - Low-power modes: Sleep, Stop and Standby
  - V<sub>BAT</sub> supply for RTC and backup registers
- Clock management
  - 4 to 32 MHz crystal oscillator
  - 32 kHz oscillator for RTC with calibration
  - Internal 8 MHz RC with x 16 PLL option
  - Internal 40 kHz oscillator
- Up to 87 fast I/Os
  - All mappable on external interrupt vectors
  - Several 5 V-tolerant
- Interconnect matrix
- 12-channel DMA controller
- Four ADCs 0.20 µS (up to 39 channels) with selectable resolution of 12/10/8/6 bits, 0 to 3.6 V conversion range, single ended/differential input, separate analog supply from 2 to 3.6 V
- Two 12-bit DAC channels with analog supply from 2.4 to 3.6 V
- Seven fast rail-to-rail analog comparators with analog supply from 2 to 3.6 V
- Four operational amplifiers that can be used in PGA mode, all terminals accessible with analog supply from 2.4 to 3.6 V
- Up to 24 capacitive sensing channels supporting touchkey, linear and rotary touch sensors





LQFP64 (10 × 10 mm) LQFP100 (14 × 14 mm)

WLCSP100 (0.4 mm pitch)

- Up to 13 timers
  - One 32-bit timer and two 16-bit timers with up to 4 IC/OC/PWM or pulse counter and quadrature (incremental) encoder input
  - Two 16-bit 6-channel advanced-control timers, with up to 6 PWM channels, deadtime generation and emergency stop
  - One 16-bit timer with 2 IC/OCs, 1 OCN/PWM, deadtime generation and emergency stop
  - Two 16-bit timers with IC/OC/OCN/PWM, deadtime generation and emergency stop
  - Two watchdog timers (independent, window)
  - SysTick timer: 24-bit downcounter
  - Two 16-bit basic timers to drive the DAC
- Calendar RTC with Alarm, periodic wakeup from Stop/Standby
- Communication interfaces
  - CAN interface (2.0B Active)
  - Two I<sup>2</sup>C Fast mode plus (1 Mbit/s) with 20 mA current sink, SMBus/PMBus, wakeup from STOP
  - Up to five USART/UARTs (ISO 7816 interface, LIN, IrDA, modem control)
  - Up to three SPIs, two with multiplexed half/full duplex I2S interface, 4 to 16 programmable bit frames
  - USB 2.0 full speed interface
  - Infrared transmitter
- Serial wire debug, Cortex®-M4 with FPU ETM, **JTAG**
- 96-bit unique ID

Table 1. Device summary

Reference	Part number
STM32F303xB	STM32F303CB, STM32F303RB, STM32F303VB
STM32F303xC	STM32F303CC, STM32F303RC, STM32F303VC

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## 1 Introduction

This datasheet provides the ordering information and mechanical device characteristics of the STM32F303xB/STM32F303xC microcontrollers.

This STM32F303xB/STM32F303xC datasheet should be read in conjunction with the STM32F303x, STM32F358xC and STM32F328x4/6/8 reference manual (RM0316). The reference manual is available from the STMicroelectronics website <a href="https://www.st.com">www.st.com</a>.

For information on the Cortex<sup>®</sup>-M4 core with FPU, please refer to:

- Cortex®-M4 with FPU Technical Reference Manual, available from ARM website www.arm.com.
- STM32F3xxx and STM32F4xxx Cortex<sup>®</sup>-M4 programming manual (PM0214) available from our website www.st.com.



# 2 Description

The STM32F303xB/STM32F303xC family is based on the high-performance ARM® Cortex®-M4 32-bit RISC core with FPU operating at a frequency of up to 72 MHz, and embedding a floating point unit (FPU), a memory protection unit (MPU) and an embedded trace macrocell (ETM). The family incorporates high-speed embedded memories (up to 256 Kbytes of Flash memory, up to 40 Kbytes of SRAM) and an extensive range of enhanced I/Os and peripherals connected to two APB buses.

The devices offer up to four fast 12-bit ADCs (5 Msps), seven comparators, four operational amplifiers, up to two DAC channels, a low-power RTC, up to five general-purpose 16-bit timers, one general-purpose 32-bit timer, and two timers dedicated to motor control. They also feature standard and advanced communication interfaces: up to two I<sup>2</sup>Cs, up to three SPIs (two SPIs are with multiplexed full-duplex I2Ss), three USARTs, up to two UARTs, CAN and USB. To achieve audio class accuracy, the I2S peripherals can be clocked via an external PLL.

The STM32F303xB/STM32F303xC family operates in the -40 to +85 °C and -40 to +105 °C temperature ranges from a 2.0 to 3.6 V power supply. A comprehensive set of power-saving mode allows the design of low-power applications.

The STM32F303xB/STM32F303xC family offers devices in four packages ranging from 48 pins to 100 pins.

The set of included peripherals changes with the device chosen.



Table 2. STM32F303xB/STM32F303xC family device features and peripheral counts

Peri	STM32F303Cx STM32F303R			-	STM32F303Vx			
Flash (Kbytes)	128	256	128	256	128	256		
SRAM (Kbytes) on data bus		32	40	32	40	32	40	
CCM (Core Coupled Memory) RAM (Kbytes)			8					
Advanced control			2 (16-bit)					
Timers	General purpose		5 (16-bit) 1 (32-bit)					
	Basic			2 (16	6-bit)			
PWM channels (	all) <sup>(1)</sup>	3	1		3	3		
PWM channels (complementary)	except	2	2		2	<u>.</u> 4		
	SPI (I2S) <sup>(2)</sup>			3(	2)			
	I <sup>2</sup> C			2				
Communication	USART	3						
interfaces	UART	(	)		2	2		
	CAN	1						
	USB	1						
CRICo	Normal I/Os (TC, TTa)	20		27 45 in LQFP10 37 in WLCSP10				
GPIOS	GPIOs  5-volt tolerant I/Os (FT, FTf)		17		25		42 in LQFP100 40 in WLCSP100	
DMA channels		12						
Capacitive sensi	ng channels	17 18 2		:4				
12-bit ADCs		4						
Number of chann	1	5	2	2	39 in LQFP100 32 in WLCSP100			
12-bit DAC chan	nels	2						
Analog compara	tor	7						
Operational amp	lifiers	4						
CPU frequency		72 MHz						
Operating voltag	е	2.0 to 3.6 V						
Operating tempe	erature	Ambient operating temperature: - 40 to 85 °C / - 40 to 105 °C Junction temperature: - 40 to 125 °C						
Packages		LQF	P48	LQF	P64		P100 SP100	

<sup>1.</sup> This total number considers also the PWMs generated on the complementary output channels

<sup>2.</sup> The SPI interfaces can work in an exclusive way in either the SPI mode or the  $I^2S$  audio mode.



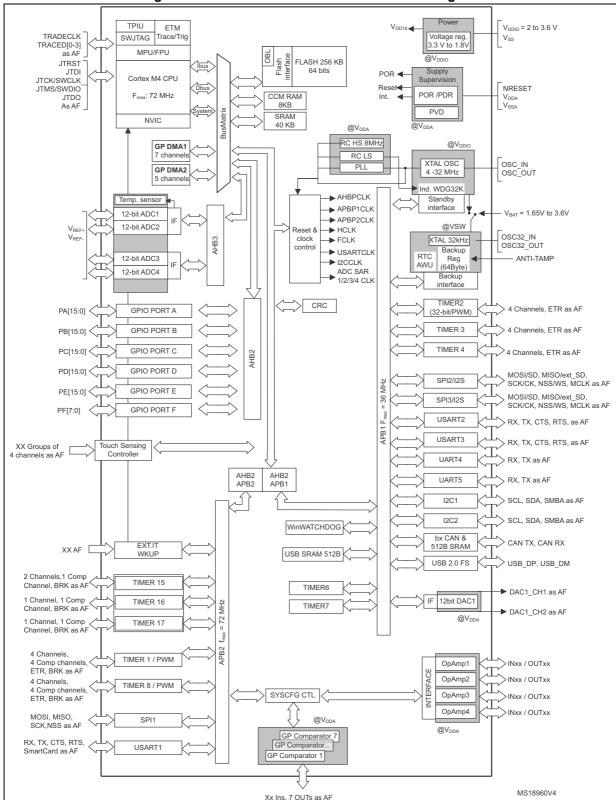


Figure 1. STM32F303xB/STM32F303xC block diagram

1. AF: alternate function on I/O pins.



## 3 Functional overview

# 3.1 ARM<sup>®</sup> Cortex<sup>®</sup>-M4 core with FPU with embedded Flash and SRAM

The ARM Cortex-M4 processor with FPU is the latest generation of ARM processors for embedded systems. It was developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced response to interrupts.

The ARM Cortex-M4 32-bit RISC processor with FPU features exceptional code-efficiency, delivering the high-performance expected from an ARM core in the memory size usually associated with 8- and 16-bit devices.

The processor supports a set of DSP instructions which allow efficient signal processing and complex algorithm execution.

Its single precision FPU speeds up software development by using metalanguage development tools, while avoiding saturation.

With its embedded ARM core, the STM32F303xB/STM32F303xC family is compatible with all ARM tools and software.

*Figure 1* shows the general block diagram of the STM32F303xB/STM32F303xC family devices.

# 3.2 Memory protection unit (MPU)

The memory protection unit (MPU) is used to separate the processing of tasks from the data protection. The MPU can manage up to 8 protection areas that can all be further divided up into 8 subareas. The protection area sizes are between 32 bytes and the whole 4 gigabytes of addressable memory.

The memory protection unit is especially helpful for applications where some critical or certified code has to be protected against the misbehavior of other tasks. It is usually managed by an RTOS (real-time operating system). If a program accesses a memory location that is prohibited by the MPU, the RTOS can detect it and take action. In an RTOS environment, the kernel can dynamically update the MPU area setting, based on the process to be executed.

The MPU is optional and can be bypassed for applications that do not need it.

# 3.3 Embedded Flash memory

All STM32F303xB/STM32F303xC devices feature up to 256 Kbytes of embedded Flash memory available for storing programs and data. The Flash memory access time is adjusted to the CPU clock frequency (0 wait state from 0 to 24 MHz, 1 wait state from 24 to 48 MHz and 2 wait states above).



#### 3.4 Embedded SRAM

STM32F303xB/STM32F303xC devices feature up to 48 Kbytes of embedded SRAM with hardware parity check. The memory can be accessed in read/write at CPU clock speed with 0 wait states, allowing the CPU to achieve 90 Dhrystone Mips at 72 MHz (when running code from the CCM (Core Coupled Memory) RAM).

- 8 Kbytes of CCM RAM mapped on both instruction and data bus, used to execute critical routines or to access data (parity check on all of CCM RAM).
- 40 Kbytes of SRAM mapped on the data bus (parity check on first 16 Kbytes of SRAM).

#### 3.5 Boot modes

At startup, Boot0 pin and Boot1 option bit are used to select one of three boot options:

- Boot from user Flash
- Boot from system memory
- Boot from embedded SRAM

The boot loader is located in the system memory. It is used to reprogram the Flash memory by using USART1 (PA9/PA10), USART2 (PD5/PD6) or USB (PA11/PA12) through DFU (device firmware upgrade).

# 3.6 Cyclic redundancy check (CRC)

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code using a configurable generator polynomial value and size.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at linktime and stored at a given memory location.

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## 3.7 Power management

#### 3.7.1 Power supply schemes

- $V_{SS}$ ,  $V_{DD}$  = 2.0 to 3.6 V: external power supply for I/Os and the internal regulator. It is provided externally through  $V_{DD}$  pins.
- $V_{SSA}$ ,  $V_{DDA}$  = 2.0 to 3.6 V: external analog power supply for ADC, DACs, comparators operational amplifiers, reset blocks, RCs and PLL. The minimum voltage to be applied to  $V_{DDA}$  differs from one analog peripheral to another. *Table 3* provides the summary of the  $V_{DDA}$  ranges for analog peripherals. The  $V_{DDA}$  voltage level must be always greater or equal to the  $V_{DD}$  voltage level and must be provided first.
- V<sub>BAT</sub> = 1.65 to 3.6 V: power supply for RTC, external clock 32 kHz oscillator and backup registers (through power switch) when V<sub>DD</sub> is not present.

rance of External analog capping randoc for animog perspirorate				
Analog peripheral	Minimum $V_{ m DDA}$ supply	Maximum V <sub>DDA</sub> supply		
ADC / COMP	2.0 V	3.6 V		
DAC / OPAMP	2.4 V	3.6V		

Table 3. External analog supply values for analog peripherals

## 3.7.2 Power supply supervision

The device has an integrated power-on reset (POR) and power-down reset (PDR) circuits. They are always active, and ensure proper operation above a threshold of 2 V. The device remains in reset mode when the monitored supply voltage is below a specified threshold, VPOR/PDR, without the need for an external reset circuit.

- The POR monitors only the V<sub>DD</sub> supply voltage. During the startup phase it is required that V<sub>DDA</sub> should arrive first and be greater than or equal to V<sub>DD</sub>.
- The PDR monitors both the V<sub>DD</sub> and V<sub>DDA</sub> supply voltages, however the V<sub>DDA</sub> power supply supervisor can be disabled (by programming a dedicated Option bit) to reduce the power consumption if the application design ensures that V<sub>DDA</sub> is higher than or equal to V<sub>DD</sub>.

The device features an embedded programmable voltage detector (PVD) that monitors the  $V_{DD}$  power supply and compares it to the VPVD threshold. An interrupt can be generated when  $V_{DD}$  drops below the  $V_{PVD}$  threshold and/or when  $V_{DD}$  is higher than the  $V_{PVD}$  threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

#### 3.7.3 Voltage regulator

The regulator has three operation modes: main (MR), low-power (LPR), and power-down.

- The MR mode is used in the nominal regulation mode (Run)
- The LPR mode is used in Stop mode.
- The power-down mode is used in Standby mode: the regulator output is in high impedance, and the kernel circuitry is powered down thus inducing zero consumption.

The voltage regulator is always enabled after reset. It is disabled in Standby mode.



#### 3.7.4 Low-power modes

The STM32F303xB/STM32F303xC supports three low-power modes to achieve the best compromise between low-power consumption, short startup time and available wakeup sources:

Sleep mode

In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.

• Stop mode

Stop mode achieves the lowest power consumption while retaining the content of SRAM and registers. All clocks in the 1.8 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled. The voltage regulator can also be put either in normal or in low-power mode.

The device can be woken up from Stop mode by any of the EXTI line. The EXTI line source can be one of the 16 external lines, the PVD output, the USB wakeup, the RTC alarm, COMPx, I2Cx or U(S)ARTx.

Standby mode

The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.8 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering Standby mode, SRAM and register contents are lost except for registers in the Backup domain and Standby circuitry.

The device exits Standby mode when an external reset (NRST pin), an IWDG reset, a rising edge on the WKUP pin or an RTC alarm occurs.

Note: The RTC, the IWDG and the corresponding clock sources are not stopped by entering Stop or Standby mode.

#### 3.8 Interconnect matrix

Several peripherals have direct connections between them. This allows autonomous communication between peripherals, saving CPU resources thus power supply consumption. In addition, these hardware connections allow fast and predictable latency.

Table 4. STM32F303xB/STM32F303xC peripheral interconnect matrix

Interconnect source Interconnect action

Interconnect source	Interconnect destination	Interconnect action	
	TIMx	Timers synchronization or chaining	
TIMx	ADCx DAC1	Conversion triggers	
	DMA	Memory to memory transfer trigger	
	Compx	Comparator output blanking	
COMPx	TIMx	Timer input: OCREF_CLR input, input capture	
ADCx	TIMx	Timer triggered by analog watchdog	



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Table 4. STM32F303xB/STM32F303xC peripheral interconnect matrix (continued)

Interconnect source	Interconnect destination	Interconnect action
GPIO RTCCLK HSE/32 MC0	TIM16	Clock source used as input channel for HSI and LSI calibration
CSS CPU (hard fault) COMPx PVD GPIO	TIM1, TIM8, TIM15, 16, 17	Timer break
	TIMx	External trigger, timer break
GPIO	ADCx DAC1	Conversion external trigger
DAC1	COMPx	Comparator inverting input

Note:

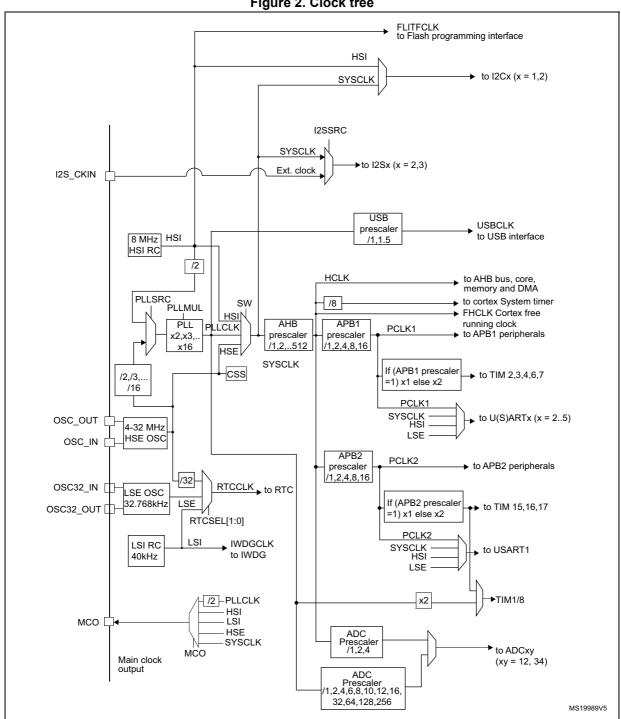
For more details about the interconnect actions, please refer to the corresponding sections in the reference manual (RM0316).

# 3.9 Clocks and startup

System clock selection is performed on startup, however the internal RC 8 MHz oscillator is selected as default CPU clock on reset. An external 4-32 MHz clock can be selected, in which case it is monitored for failure. If failure is detected, the system automatically switches back to the internal RC oscillator. A software interrupt is generated if enabled. Similarly, full interrupt management of the PLL clock entry is available when necessary (for example with failure of an indirectly used external oscillator).

Several prescalers allow to configure the AHB frequency, the high speed APB (APB2) and the low speed APB (APB1) domains. The maximum frequency of the AHB and the high speed APB domains is 72 MHz, while the maximum allowed frequency of the low speed APB domain is 36 MHz.

Figure 2. Clock tree





# 3.10 General-purpose input/outputs (GPIOs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain), as input (with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions. All GPIOs are high current capable except for analog inputs.

The I/Os alternate function configuration can be locked if needed following a specific sequence in order to avoid spurious writing to the I/Os registers.

Fast I/O handling allows I/O toggling up to 36 MHz.

# 3.11 Direct memory access (DMA)

The flexible general-purpose DMA is able to manage memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers. The DMA controller supports circular buffer management, avoiding the generation of interrupts when the controller reaches the end of the buffer.

Each of the 12 DMA channels is connected to dedicated hardware DMA requests, with software trigger support for each channel. Configuration is done by software and transfer sizes between source and destination are independent.

The DMA can be used with the main peripherals: SPI,  $I^2C$ , USART, general-purpose timers, DAC and ADC.

# 3.12 Interrupts and events

## 3.12.1 Nested vectored interrupt controller (NVIC)

The STM32F303xB/STM32F303xC devices embed a nested vectored interrupt controller (NVIC) able to handle up to 66 maskable interrupt channels and 16 priority levels.

The NVIC benefits are the following:

- Closely coupled NVIC gives low latency interrupt processing
- Interrupt entry vector table address passed directly to the core
- Closely coupled NVIC core interface
- Allows early processing of interrupts
- Processing of late arriving higher priority interrupts
- Support for tail chaining
- Processor state automatically saved
- Interrupt entry restored on interrupt exit with no instruction overhead

The NVIC hardware block provides flexible interrupt management features with minimal interrupt latency.

## 3.13 Fast analog-to-digital converter (ADC)

four fast analog-to-digital converters 5 MSPS, with selectable resolution between 12 and 6 bit, are embedded in the STM32F303xB/STM32F303xC family devices. The ADCs have up to 39 external channels. Some of the external channels are shared between ADC1&2 and between ADC3&4. Channels can be configured to be either single-ended input or differential input. The ADCs can perform conversions in single-shot or scan modes. In scan mode, automatic conversion is performed on a selected group of analog inputs.

The ADCs have also internal channels: Temperature sensor connected to ADC1 channel 16,  $V_{BAT/2}$  connected to ADC1 channel 17, Voltage reference  $V_{REFINT}$  connected to the 4 ADCs channel 18, VOPAMP1 connected to ADC1 channel 15, VOPAMP2 connected to ADC2 channel 17, VREFOPAMP3 connected to ADC3 channel 17 and VREFOPAMP4 connected to ADC4 channel 17.

Additional logic functions embedded in the ADC interface allow:

- Simultaneous sample and hold
- Interleaved sample and hold
- Single-shunt phase current reading techniques.

The ADC can be served by the DMA controller. 3 analog watchdogs per ADC are available.

An analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

The events generated by the general-purpose timers and the advanced-control timers (TIM1 and TIM8) can be internally connected to the ADC start trigger and injection trigger, respectively, to allow the application to synchronize A/D conversion and timers.

#### 3.13.1 Temperature sensor

The temperature sensor (TS) generates a voltage  $V_{SENSE}$  that varies linearly with temperature.

The temperature sensor is internally connected to the ADC1\_IN16 input channel which is used to convert the sensor output voltage into a digital value.

The sensor provides good linearity but it has to be calibrated to obtain good overall accuracy of the temperature measurement. As the offset of the temperature sensor varies from chip to chip due to process variation, the uncalibrated internal temperature sensor is suitable for applications that detect temperature changes only.

To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the system memory area, accessible in read-only mode.

## 3.13.2 Internal voltage reference (V<sub>REFINT</sub>)

The internal voltage reference ( $V_{REFINT}$ ) provides a stable (bandgap) voltage output for the ADC and Comparators.  $V_{REFINT}$  is internally connected to the ADCx\_IN18, x=1...4 input channel. The precise voltage of  $V_{REFINT}$  is individually measured for each part by ST during production test and stored in the system memory area. It is accessible in read-only mode.

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## 3.13.3 V<sub>BAT</sub> battery voltage monitoring

This embedded hardware feature allows the application to measure the  $V_{BAT}$  battery voltage using the internal ADC channel ADC1\_IN17. As the  $V_{BAT}$  voltage may be higher than  $V_{DDA}$ , and thus outside the ADC input range, the  $V_{BAT}$  pin is internally connected to a bridge divider by 2. As a consequence, the converted digital value is half the  $V_{BAT}$  voltage.

#### 3.13.4 OPAMP reference voltage (VREFOPAMP)

Every OPAMP reference voltage can be measured using a corresponding ADC internal channel: VREFOPAMP1 connected to ADC1 channel 15, VREFOPAMP2 connected to ADC2 channel 17, VREFOPAMP3 connected to ADC3 channel 17, VREFOPAMP4 connected to ADC4 channel 17.

# 3.14 Digital-to-analog converter (DAC)

Two 12-bit buffered DAC channels can be used to convert digital signals into analog voltage signal outputs. The chosen design structure is composed of integrated resistor strings and an amplifier in inverting configuration.

This digital interface supports the following features:

- Two DAC output channels
- 8-bit or 10-bit monotonic output
- Left or right data alignment in 12-bit mode
- Synchronized update capability
- Noise-wave generation
- Triangular-wave generation
- Dual DAC channel independent or simultaneous conversions
- DMA capability (for each channel)
- External triggers for conversion

# 3.15 Operational amplifier (OPAMP)

The STM32F303xB/STM32F303xC embeds four operational amplifiers with external or internal follower routing and PGA capability (or even amplifier and filter capability with external components). When an operational amplifier is selected, an external ADC channel is used to enable output measurement.

The operational amplifier features:

- 8.2 MHz bandwidth
- 0.5 mA output capability
- Rail-to-rail input/output
- In PGA mode, the gain can be programmed to be 2, 4, 8 or 16.

# 3.16 Fast comparators (COMP)

The STM32F303xB/STM32F303xC devices embed seven fast rail-to-rail comparators with programmable reference voltage (internal or external), hysteresis and speed (low speed for low-power) and with selectable output polarity.

The reference voltage can be one of the following:

- External I/O
- DAC output pin
- Internal reference voltage or submultiple (1/4, 1/2, 3/4). Refer to *Table 28: Embedded internal reference voltage on page 62* for the value and precision of the internal reference voltage.

All comparators can wake up from STOP mode, generate interrupts and breaks for the timers and can be also combined per pair into a window comparator

# 3.17 Timers and watchdogs

The STM32F303xB/STM32F303xC includes two advanced control timers, up to six general-purpose timers, two basic timers, two watchdog timers and a SysTick timer. The table below compares the features of the advanced control, general purpose and basic timers.

**DMA** Capture/ Counter Counter **Prescaler** Complementary Timer type **Timer** request compare resolution type factor outputs generation Channels Any integer TIM1, Up, Down, Advanced 16-bit between 1 Yes 4 Yes TIM8 Up/Down and 65536 Any integer General-Up, Down, TIM2 32-bit between 1 Yes No Up/Down purpose and 65536 Any integer General-Up, Down, TIM3. TIM4 16-bit Yes between 1 No Up/Down purpose and 65536 Any integer General-TIM15 16-bit Up between 1 Yes 2 1 purpose and 65536 Any integer General-**TIM16, TIM17** 16-bit Up between 1 Yes 1 1 purpose and 65536 Any integer TIM6, Basic 16-bit Up between 1 Yes 0 No TIM7 and 65536

Table 5. Timer feature comparison

Note: TIM1/8 can have PLL as clock source, and therefore can be clocked at 144 MHz.

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# 3.17.1 Advanced timers (TIM1, TIM8)

The advanced-control timers (TIM1 and TIM8) can each be seen as a three-phase PWM multiplexed on six channels. They have complementary PWM outputs with programmable inserted dead-times. They can also be seen as complete general-purpose timers. The four independent channels can be used for:

- Input capture
- Output compare
- PWM generation (edge or center-aligned modes) with full modulation capability (0-100%)
- One-pulse mode output

In debug mode, the advanced-control timer counter can be frozen and the PWM outputs disabled to turn off any power switches driven by these outputs.

Many features are shared with those of the general-purpose TIM timers (described in Section 3.17.2 using the same architecture, so the advanced-control timers can work together with the TIM timers via the Timer Link feature for synchronization or event chaining.

#### 3.17.2 General-purpose timers (TIM2, TIM3, TIM4, TIM15, TIM16, TIM17)

There are up to six synchronizable general-purpose timers embedded in the STM32F303xB/STM32F303xC (see *Table 5* for differences). Each general-purpose timer can be used to generate PWM outputs, or act as a simple time base.

TIM2, 3, and TIM4

These are full-featured general-purpose timers:

- TIM2 has a 32-bit auto-reload up/downcounter and 32-bit prescaler
- TIM3 and 4 have 16-bit auto-reload up/downcounters and 16-bit prescalers.

These timers all feature 4 independent channels for input capture/output compare, PWM or one-pulse mode output. They can work together, or with the other general-purpose timers via the Timer Link feature for synchronization or event chaining.

The counters can be frozen in debug mode.

All have independent DMA request generation and support quadrature encoders.

TIM15, 16 and 17

These three timers general-purpose timers with mid-range features:

They have 16-bit auto-reload upcounters and 16-bit prescalers.

- TIM15 has 2 channels and 1 complementary channel
- TIM16 and TIM17 have 1 channel and 1 complementary channel

All channels can be used for input capture/output compare, PWM or one-pulse mode output.

The timers can work together via the Timer Link feature for synchronization or event chaining. The timers have independent DMA request generation.

The counters can be frozen in debug mode.

#### 3.17.3 Basic timers (TIM6, TIM7)

These timers are mainly used for DAC trigger generation. They can also be used as a generic 16-bit time base.



#### 3.17.4 Independent watchdog (IWDG)

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 40 kHz internal RC and as it operates independently from the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free running timer for application timeout management. It is hardware or software configurable through the option bytes. The counter can be frozen in debug mode.

#### 3.17.5 Window watchdog (WWDG)

The window watchdog is based on a 7-bit downcounter that can be set as free running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in debug mode.

#### 3.17.6 SysTick timer

This timer is dedicated to real-time operating systems, but could also be used as a standard down counter. It features:

- A 24-bit down counter
- Autoreload capability
- Maskable system interrupt generation when the counter reaches 0.
- Programmable clock source

# 3.18 Real-time clock (RTC) and backup registers

The RTC and the 16 backup registers are supplied through a switch that takes power from either the  $V_{DD}$  supply when present or the  $V_{BAT}$  pin. The backup registers are sixteen 32-bit registers used to store 64 bytes of user application data when  $V_{DD}$  power is not present.

They are not reset by a system or power reset, or when the device wakes up from Standby mode.

The RTC is an independent BCD timer/counter. It supports the following features:

- Calendar with subsecond, seconds, minutes, hours (12 or 24 format), week day, date, month, year, in BCD (binary-coded decimal) format.
- Reference clock detection: a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision.
- Automatic correction for 28, 29 (leap year), 30 and 31 days of the month.
- Two programmable alarms with wake up from Stop and Standby mode capability.
- On-the-fly correction from 1 to 32767 RTC clock pulses. This can be used to synchronize it with a master clock.
- Digital calibration circuit with 1 ppm resolution, to compensate for quartz crystal inaccuracy.
- Three anti-tamper detection pins with programmable filter. The MCU can be woken up from Stopand Standby modes on tamper event detection.
- Timestamp feature which can be used to save the calendar content. This function can
  be triggered by an event on the timestamp pin, or by a tamper event. The MCU can be
  woken up from Stop and Standby modes on timestamp event detection.

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 17-bit Auto-reload counter for periodic interrupt with wakeup from STOP/STANDBY capability.

The RTC clock sources can be:

- A 32.768 kHz external crystal
- A resonator or oscillator
- The internal low-power RC oscillator (typical frequency of 40 kHz)
- The high-speed external clock divided by 32.

# 3.19 Inter-integrated circuit interface (I<sup>2</sup>C)

Up to two l<sup>2</sup>C bus interfaces can operate in multimaster and slave modes. They can support standard (up to 100 KHz), fast (up to 400 KHz) and fast mode + (up to 1 MHz) modes.

Both support 7-bit and 10-bit addressing modes, multiple 7-bit slave addresses (2 addresses, 1 with configurable mask). They also include programmable analog and digital noise filters.

Table 6. Comparison of I2C analog and digital filters

	Analog filter	Digital filter
Pulse width of suppressed spikes	50 ns	Programmable length from 1 to 15 I2C peripheral clocks
Benefits	Available in Stop mode	Extra filtering capability vs. standard requirements.     Stable length
Drawbacks	Variations depending on temperature, voltage, process	Wakeup from Stop on address match is not available when digital filter is enabled.

In addition, they provide hardware support for SMBUS 2.0 and PMBUS 1.1: ARP capability, Host notify protocol, hardware CRC (PEC) generation/verification, timeouts verifications and ALERT protocol management. They also have a clock domain independent from the CPU clock, allowing the I2Cx (x=1,2) to wake up the MCU from Stop mode on address match.

The I2C interfaces can be served by the DMA controller.

Refer to *Table 7* for the features available in I2C1 and I2C2.

Table 7. STM32F303xB/STM32F303xC I<sup>2</sup>C implementation

I2C features <sup>(1)</sup>	I2C1	I2C2
7-bit addressing mode	X	Х
10-bit addressing mode	Х	Х
Standard mode (up to 100 kbit/s)	Х	Х
Fast mode (up to 400 kbit/s)	Х	Х
Fast Mode Plus with 20mA output drive I/Os (up to 1 Mbit/s)	Х	Х
Independent clock	Х	Х

